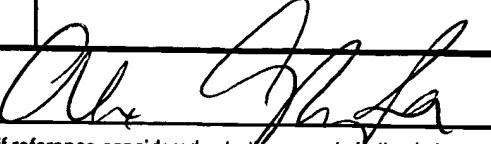
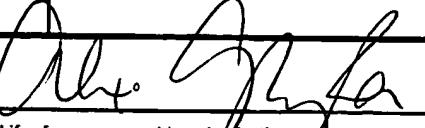


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				John MACNEIL			
				FILING August 12, 2003		GROUP To Be Assigned	
				U.S. PATENT DOCUMENTS			
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>AC</i>	A	3,223,040	12/14/1965	DINKELKAMP			
	B	4,793,524	12/27/1998	STARR			
	C	5,095,938	03/17/1992	GARRISON			
	D	5,098,741	03/24/1992	NOLET ET AL.			
	E	5,195,655	03/23/1993	BUKHMAN			
	F	5,356,034	10/18/1994	SCHLUMBERGER			
	G	5,534,069	07/09/1996	KUWABARA ET AL.			
	H	5,620,524	04/15/1997	FAN ET AL.			
	I	5,730,804	03/24/1998	GOMI ET AL.			
	J	5,876,503	03/02/1999	ROEDER ET AL.			
<i>AC</i>	K	5,273,851	12/28/1993	TAKEI ET AL.			
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
							YES
<i>AC</i>	L	GB 2 108 133 A	05/11/1983	UNITED KINGDOM			
	M	GB 2 280 169 A	01/25/1995	UNITED KINGDOM			
	N	GB 2 111 064 A	06/29/1983	UNITED KINGDOM			
<i>AC</i>	O	EP 0 826 791 A2	03/04/1998	EPO			
<i>AC</i>	P	EP 0 212 691 A1	03/04/1987	EPO			
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
<i>AC</i>	Q	EPO, PATENT ABSTRACTS OF JAPAN, PUBLICATION NO. 10310866, PUBLICATION DATE 24-11-98, Kamiya Kazuo					
<i>AC</i>	R	A. Grill et al., "Low dielectric constant films prepared by plasma-enhanced chemical vapor deposition from tetramethylsilane," Journal of Applied Physics, Volume 85, Number 6, 15 March 1999, pages 3314-3318.					
EXAMINER <i>Ac</i>				DATE CONSIDERED <i>4/28/04</i>			
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							

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AC	S	5,273,851	12/28/1993	TAKAE ET AL.				
	T	5,314,724	05/24/1994	TSUKUNE ET AL.				
	U	5,494,712	02/27/1996	HU ET AL.				
	V	5,593,741	01/14/1997	IKEDA				
	W	5,641,559	06/24/1997	NAMIKI				
	X	5,786,039	07/28/1998	BROUQUET				
	Y	4,096,315	06/20/1978	KUBACKI				
	Z	4,822,632	04/18/1989	WILLIAMS ET AL.				
	AA	4,894,254	01/16/1990	NAKAYAMA ET AL.				
AC	BB	5,270,267	12/14/1993	OUELLET				
FOREIGN PATENT DOCUMENTS								
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
AC	CC	EP 0 726 599 A2	08/14/1996	EPO			YES	NO
	DD	EP 0 529 334 A2	03/03/1993	EPO			YES	NO
	EE	G 2 220 869 A	01/24/1990	UNITED KINGDOM			YES	NO
	FF	EP 0 254 205 A2	01/27/1998	EPO			YES	NO
AC	GG	WO 96/29576	09/26/1996	PCT			YES	NO
OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>								
EXAMINER				DATE CONSIDERED	4/18/04			
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FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
								YES
<i>AC</i>	HH	WO 98/23787	06/04/1998	PCT				
<i>J</i>	II	WO 99/43866	09/02/1999	PCT				
<i>J</i>	JJ	WO 01/01472 A1	01/04/2001	PCT				
	KK	WO 94/01885	01/20/1994	PCT				
<i>AG</i>	LL	DE 19654 737 A1	12/30/1996	GERMANY				
OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>								
EXAMINER				DATE CONSIDERED	<i>4/18/04</i>			
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				John MACNEIL	FILING	GROUP	To Be Assigned	
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*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
FOREIGN PATENT DOCUMENTS								
AC		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
		MM	EP 0 761 841 A1	03/12/1997	EPO			YES
AC	NN	WO 98/08249	02/26/1998	PCT				
AC	OO	0 519 079 A1	12/23/1992	EPO				
AC	PP	WO 00/51174	08/31/2000	PCT				
AC	QQ	0159079	12/1992	EPO				
OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>								
EXAMINER				DATE CONSIDERED		4/28/04		

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